

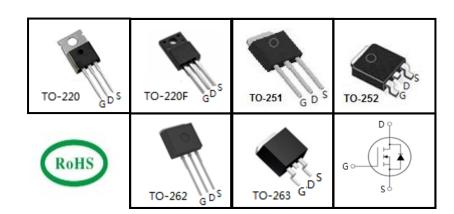
650V Super-Junction Power MOSFET

FEATURES

- Very low FOM $R_{DS(on)} \times Q_g$
- 100% avalanche tested
- RoHS compliant

APPLICATIONS

- Switch Mode Power Supply (SMPS)
- Uninterruptible Power Supply (UPS)
- Power Factor Correction (PFC)



Device Marking and Package Information						
Device	TPP65R940C	TPA65R940C	TPU65R940C	TPD65R940C	TPC65R940C	TPB65R940C
Package	TO-220	TO-220F	TO-251	TO-252	TO-262	TO-263
Marking	65R940C	65R940C	65R940C	65R940C	65R940C	65R940C

Absolute Maximum Ratings $T_C = 25^{\circ}C$, unless otherwise noted					
Barrantar	0	Value		11.2	
Parameter	Symbol	TO-251, TO-252	TO-220F	Unit	
Drain-Source Voltage (V _{GS} = 0V)	V _{DSS}	650	650		
Continuous Drain Current	I _D	4		Α	
Pulsed Drain Current (note1)	I _{DM}	12		А	
Gate-Source Voltage	V_{GSS}	±30		V	
Single Pulse Avalanche Energy (note2)	E _{AS}	52.8		mJ	
Avalanche Current (note1)	I _{AR}	0.8		А	
Repetitive Avalanche Energy (note1)	E _{AR}	0.09		mJ	
Power Dissipation (T _C = 25°C)	P _D	28 23		W	
Operating Junction and Storage Temperature Range	T _J , T _{stg}	-55~+150		°C	

Thermal Resistance					
Baranatar	Comple ed	Value		1124	
Parameter	Symbol	TO-251, TO-252	TO-220F	Unit	
Thermal Resistance, Junction-to-Case	R _{thJC}	4.4	5.5	°C/W	
Thermal Resistance, Junction-to-Ambient	R _{thJA}	62	80	°C/VV	



TPP65R940C, TPA65R940C, TPU65R940C, TPD65R940C, TPC65R940C, TPB65R940C

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Davamatav			Value				
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static		•					
Drain-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0V, I_D = 250\mu A$	650			V	
Zero Gate Voltage Drain Current		$V_{DS} = 650V, V_{GS} = 0V, T_{J} = 25^{\circ}C$			1		
Zero Gate voltage Drain Current	I _{DSS}	$V_{DS} = 650 \text{V}, V_{GS} = 0 \text{V}, T_{J} = 150^{\circ} \text{C}$			100	μA	
Gate-Source Leakage	$I_{\rm GSS}$	$V_{GS} = \pm 30V$			±100	nA	
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.5		4.0	V	
Drain-Source On-Resistance (Note3)	R _{DS(on)}	V _{GS} = 10V, I _D = 1A		0.88	1.0	Ω	
Forward Transconductance (Note3)	g _{fs}	V _{DS} = 10V, I _D = 1A		3		S	
Dynamic							
Input Capacitance	C _{iss}	V 0V		350		pF	
Output Capacitance	C _{oss}	$V_{GS} = 0V,$ $V_{DS} = 50V,$		20			
Reverse Transfer Capacitance	C _{rss}	f = 1.0MHz		2.6			
Total Gate Charge	Q_g			7		nC	
Gate-Source Charge	Q_{gs}	$V_{DD} = 520V, I_{D} = 4A, V_{GS} = 10V$		1.5			
Gate-Drain Charge	Q_{gd}	- 65		2.5			
Turn-on Delay Time	t _{d(on)}			36			
Turn-on Rise Time	t _r	$V_{DD} = 400V, I_{D} = 4A,$		27			
Turn-off Delay Time	t _{d(off)}	$R_G = 25\Omega$		79		ns ns	
Turn-off Fall Time	t _f			29			
Drain-Source Body Diode Characteris	stics						
Continuous Body Diode Current	I _S	T 0500			3.9	Δ.	
Pulsed Diode Forward Current	I _{SM}	T _C = 25°C			12	Α	
Body Diode Voltage	V _{SD}	$T_J = 25^{\circ}C$, $I_{SD} = 4A$, $V_{GS} = 0V$		0.9	1.2	V	
Reverse Recovery Time	t _{rr}			220		ns	
Reverse Recovery Charge	verse Recovery Charge Q_{rr} $V_R = 480V, I_F = I_S, di_F/dt = 100A/\mu s$			0.9		μC	
Peak Reverse Recovery Current	I _{rrm}			8		Α	

Notes

- 1. Repetitive Rating: Pulse Width limited by maximum junction temperature
- 2. $I_{AS} = 0.8A$, $V_{DD} = 50V$, $R_G = 25\Omega$, Starting $T_J = 25^{\circ}C$
- 3. Pulse Test: Pulse Width ≤ 300µs, Duty Cycle ≤ 1%

Typical Characteristics $T_J = 25^{\circ}$ C, unless otherwise noted

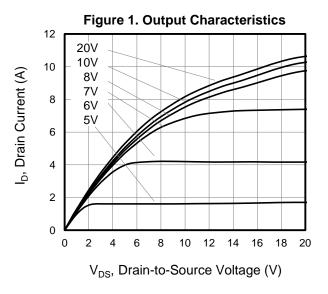


Figure 3. On-Resistance vs. Drain Current

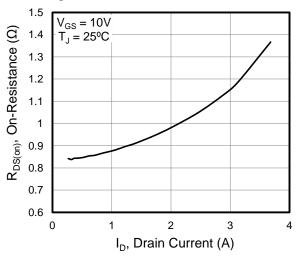


Figure 5. Gate Charge

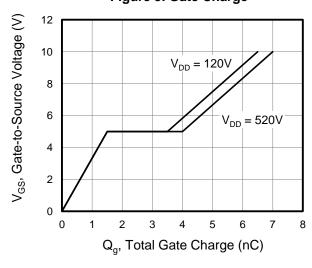


Figure 2. Transfer Characteristics

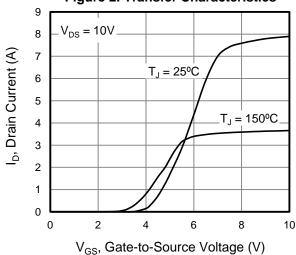


Figure 4. Capacitance

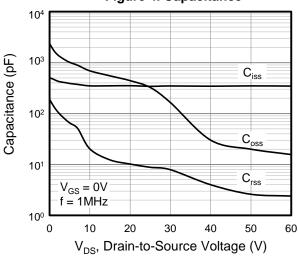
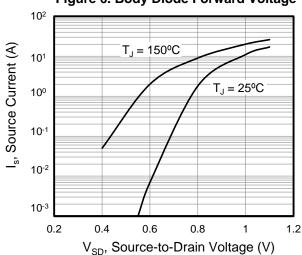


Figure 6. Body Diode Forward Voltage





Typical Characteristics $T_J = 25^{\circ}C$, unless otherwise noted

Figure 7. On-Resistance vs. **Junction Temperature** 3 $V_{GS} = 10V$ $I_D = 2A$ R_{DS(on)}, (Normalized) 2.5 1.5 1 0.5 0 0 -100 -50 50 100 150

-0.2 -0.4 -0.6 -0.8 -1 -1.2 -100 -50 200 T_J, Junction Temperature (°C)

Figure 8. Threshold Voltage vs. **Junction Temperature** 0.6 $I_{D} = 250 \mu A$ 0.4 V_{GS(th)}, (Variance)we 0.2 0 100 150 200 T_J, Junction Temperature (°C)

Figure 9. Transient Thermal Impedance TO-251,TO-252 Z_{thJC}, Thermal Impedance (K/W) 10¹ 10⁰ D = 0.510-1 D = 0.2D = 0.1D = 0.0510-2 D = 0.02D = 0.01Single Pulse 10-3 T_p, Pulse Width (s)

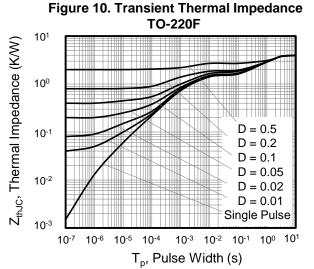




Figure A: Gate Charge Test Circuit and Waveform

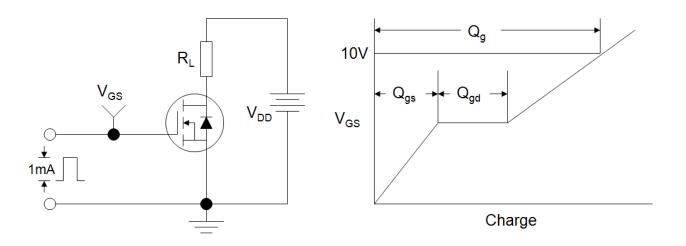


Figure B: Resistive Switching Test Circuit and Waveform

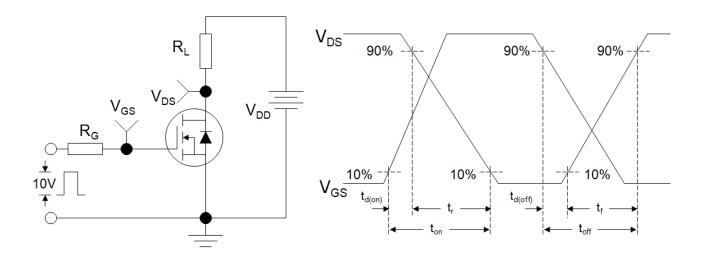
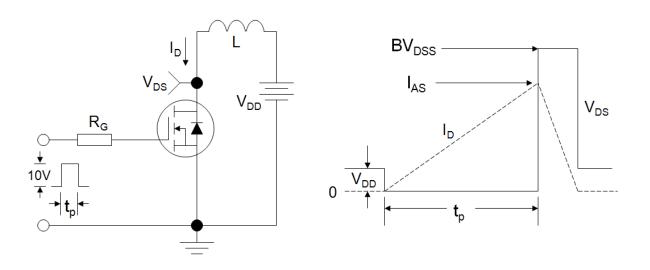
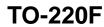
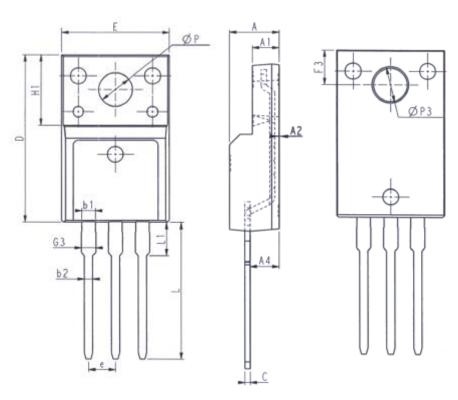


Figure C: Unclamped Inductive Switching Test Circuit and Waveform



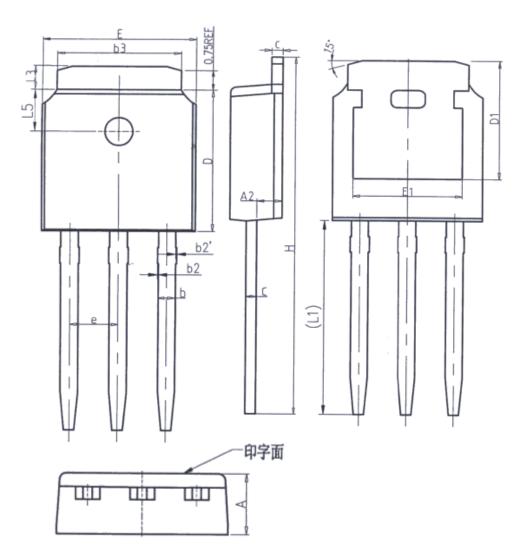






Unit: mm			Unit: mm			
Symbol	Min.	Max.	Symbol	Min.	Max.	
E	9. 96	10.36	L	12. 68	13. 28	
Α	4. 50	4. 90	L1	2. 93	3. 13	
A1	2. 34	2. 74	Р	3. 03	3. 38	
A2	0. 30	0. 60	Р3	3. 15	3. 65	
A4	2. 56	2. 96	F3	3. 15	3. 45	
С	0. 40	0. 65	G3	1. 25	1. 55	
D	15. 57	16. 17	b1	1. 18	1. 43	
H1	6. 70REF		b2	0. 70	0. 95	
е	2. 54BSC					

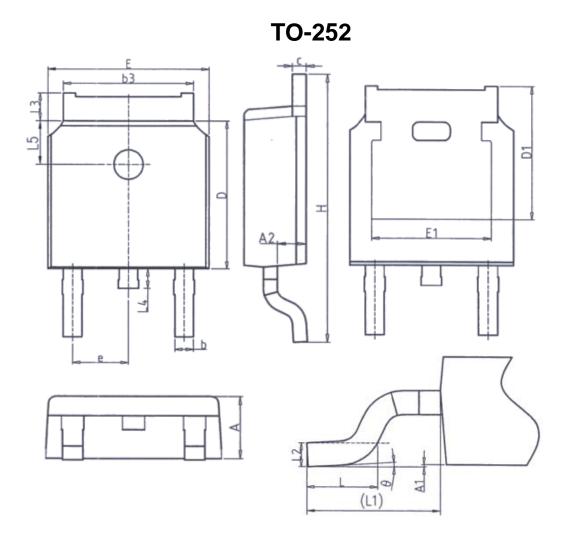
TO-251



l	Unit: mm			
Symbol	Min.	Max.		
Α	2. 20	2. 40		
A2	0. 97	1. 17		
b	0. 68	0. 90		
b2	0.00	0.10		
b2′	0.00	0.10		
b3	5. 20	5. 50		
С	0. 43	0. 63		
D	5. 98	6. 22		

Unit: mm				
Symbol	Min.	Max.		
D1	5. 30	REF		
E	6. 40	6. 80		
E1	4. 63	-		
е	2. 286BSC			
Н	16. 22	16. 82		
L1	9. 15	9. 65		
L3	0.88	1. 28		
L5	1. 65	1. 95		





Unit: mm				
Symbol	Min.	Max.		
Α	2. 20	2. 40		
A1	0.00	0. 20		
A2	0. 97	1. 17		
b	0. 68	0.90		
b3	5. 20	5. 50		
С	0. 43	0. 63		
D	5. 98	6. 22		
D1	5. 30	REF		
E	6. 40	6. 80		
E1	4. 63	_		

Unit: mm				
Symbol	Min. Max.			
е	e 2. 286BSC			
Н	9. 40	10.50		
L	1. 38	1. 75		
L1	L1 2. 90REF			
L2	0. 51	IBSC		
L3	0.88	1. 28		
L4	_	1.00		
L5	1. 65	1. 95		
θ	0°	8°		



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